

**Search Notes**

Application/Control No.

10/688,429

Examiner

Feben M. Haile

Applicant(s)/Patent under  
Reexamination

HEFTY ET AL.

Art Unit

2616

**SEARCHED**

Class	Subclass	Date	Examiner
370	231	4/30/2007	FH
370	236	4/30/2007	FH
370	395.71	4/30/2007	FH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search: buffer, queue, storage, memory, credit,	4/30/2007	FH